

Notice of References Cited

Application/Control No.

10/674,292

Applicant(s)/Patent Under
Reexamination
HASEI ET AL.

Examiner

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Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2003/0008217	01-2003	Kobayashi, Hironori	430/5
	C	US-2003/0059686	03-2003	Kobayashi et al.	430/5
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NON-PATENT DOCUMENTS

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